Notice of References Cited 10/624,985 Reexamination OHNO ET AL. Examiner Craig A. Thompson Reexamination OHNO ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*	İ	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,515,309	02-2003	Tohyama et al.	257/88
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	7	US-			
	К	US-			
	L	US-		·	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		·			
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	Holl Albit Boometre							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	\ \							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under